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Application No. <u>09/653,411</u>	Prepared by <u>NPB</u>	Tracking Number <u>05,895,991</u>	
Examiner-GAU <u>Eckert - 2815</u>	Date <u>3/10/04</u>	Week Date <u>1/26/04</u>	
	No. of queries <u>2</u>	<u>1PW</u>	

JACKET			
a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

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<b>CLAIMS</b>	
a. Claim(s) Missing	<p><i>Thompson</i></p> <p>initials <i>OKM</i></p>
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3/30/04



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Substitute for form 1449/APTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)			<b>Complete If Known</b>		
			Application Number	09/653,411	
			Filing Date	August 31, 2000	
			First Named Inventor	Whonchee Lee	
			Art Unit	2815	
			Examiner Name	Joseph H. Nguyen	
Sheet	1	of	3	Attorney Docket Number	M4065.0361/P361

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cts No.	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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JN	AA	2001/0036746	11-01-2001	Sato et al.	
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1675112 v1; ZWSW011.DOC



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				Application Number	09/653,411
				Filing Date	August 31, 2000
				First Named Inventor	Whonchee Lee
				Art Unit	2815
				Examiner Name	Joseph H. Nguyen
Sheet	2	of	3	Attorney Docket Number	M4065.0361/P361

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Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Foreign Patent Document <sup>2</sup> Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
JN	BA	EP 0 459 397 A2	12-04-1991	Naoto Miyashita		
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<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See attached Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the application number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
JN	CA	KONDO, S. et al., "Abrasive-Free Polishing for Copper Damascene Interconnection," Journal of the Electrochemical Society, Vol. 147, No. 10, pp. 3907-3913, (2000)	
	CB	D'HEURLE, F.M. and K.C. PARK, IBM Technical Disclosure Bulletin, Electrolytic Process for Metal Pattern Generation, Vol. 17, No. 1, pp. 271-272, June 1974, XP-002235691, NN 7406271.	
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		Filing Date	August 31, 2000		
		First Named Inventor	Whonchee Lee		
		Group Art Unit	2815		
		Examiner Name	Joseph H. Nguyen		
Sheet	3	of	3	Attorney Docket Number	M4065.0361/P361

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Examiner Signature	JOSEPH H. NGUYEN	Date Considered	11/10/04
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